

Search Notes



Application/Control No.

10/757,974

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

TIHANYI, JENOE

Art Unit

2816

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|----------|----------|
| 327 | 380 | 02.07.05 | NW |
| | 383 | ↓ | ↓ |
| | 384 | ↓ | ↓ |
| | 427 | ↓ | ↓ |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|----------------------------|----------|------|
| EAST See attachment | 02.07.05 | NW |
| Consulted with Tuan Lam | 02.07.05 | NW |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |